

# Tunable point contacts in dynamic atomic force/scanning tunneling microscopy

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In 1995 it was shown that dynamic atomic force microscopy (AFM) allows to obtain true atomic resolution by force microscopy in vacuum. In this technique, a cantilever with a stiffness of  $k \approx 10$  N/m, supplied with a sharp tip at its end is vibrating with an amplitude of  $A \approx 20$  nm. The forces between tip and sample cause a detectable frequency shift, which ultimately is used to image surfaces. Frequency modulation AFM is now a standard technique [1] and allows to image conducting and nonconducting samples with atomic resolution. Recently, the technique was improved by increasing the cantilever stiffness to  $k \approx 2000$  N/m and reducing the amplitude to  $A \approx 1$  nm. Features within single atoms (orbitals) have been imaged [2] with this low-amplitude technique. The small amplitudes also allow two new types of experiments: i) lateral force imaging with true atomic resolution of conservative and dissipative interactions [3] and ii) dynamic scanning tunneling (STM) microscope experiments [4] where orbital contributions similar to the nano-bridge experiments by Scheer et al. [5] are measured. The tip-sample system in dynamic AFM/STM thus is a tunable nanocontact, allowing the study of currents, forces and dissipation between single atoms.

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[4] M. Herz et al., in preparation.

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